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Test Report

No.: EKR26501876 Date: 05-Jun-2026

NXP SEMICONDUCTORS
HIGH TECH CAMPUS 60, 5656AG EINDHOVEN, THE NETHERLANDS

The following sample(s) was/were submitted and identified by the applicant as:

Sample Submitted By : NXP SEMICONDUCTORS NETHERLANDS B.V.
Sample Name : ATMC WAFER

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Sample Receiving Date : 29-May-2026
Testing Period : 29-May-2026 to 05-Jun-2026

Test Requested : (1) As specified by client, with reference to RoHS 2011/65/EU Annex II and amending Directive (EU) 2015/863 to determine Cadmium, Lead, Mercury, Cr(VI), PBBs, PBDEs, DBP, BBP, DEHP, DIBP contents in the submitted sample(s).
(2) Please refer to next pages for the other item(s).

Test Results : Please refer to following pages.

Conclusion : (1) Based on the performed tests on submitted sample(s), the test results of Cadmium, Lead, Mercury, Cr(VI), PBBs, PBDEs, DBP, BBP, DEHP, DIBP comply with the limits as set by RoHS Directive (EU) 2015/863 amending Annex II to Directive 2011/65/EU.

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Ray Chang, Ph.D./Department Manager
Signed for and on behalf of
SGS TAIWAN LTD.
Chemical Laboratory-Kaohsiung

CHECK REPORT
PIN CODE: 33DE4ED2

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Test Part Description

No.1 : WAFER

Test Result(s)

Test Item(s)	Method	Unit	MDL	Result No.1	Limit
Cadmium (Cd)	With reference to IEC 62321-5: 2013, analysis was performed by ICP-OES.	mg/kg	2	n.d.	100
Lead (Pb)		mg/kg	2	n.d.	1000
Mercury (Hg)	With reference to IEC 62321-4: 2013+ AMD1: 2017, analysis was performed by ICP-OES.	mg/kg	2	n.d.	1000
Hexavalent Chromium Cr(VI)	With reference to IEC 62321-7-2: 2017, analysis was performed by UV-VIS.	mg/kg	8	n.d.	1000
Monobromobiphenyl	With reference to IEC 62321-6: 2015, analysis was performed by GC/MS.	mg/kg	5	n.d.	-
Dibromobiphenyl		mg/kg	5	n.d.	-
Tribromobiphenyl		mg/kg	5	n.d.	-
Tetrabromobiphenyl		mg/kg	5	n.d.	-
Pentabromobiphenyl		mg/kg	5	n.d.	-
Hexabromobiphenyl		mg/kg	5	n.d.	-
Heptabromobiphenyl		mg/kg	5	n.d.	-
Octabromobiphenyl		mg/kg	5	n.d.	-
Nonabromobiphenyl		mg/kg	5	n.d.	-
Decabromobiphenyl		mg/kg	5	n.d.	-
Sum of PBBs		mg/kg	-	n.d.	1000
Monobromodiphenyl ether		mg/kg	5	n.d.	-
Dibromodiphenyl ether		mg/kg	5	n.d.	-
Tribromodiphenyl ether		mg/kg	5	n.d.	-
Tetrabromodiphenyl ether		mg/kg	5	n.d.	-
Pentabromodiphenyl ether		mg/kg	5	n.d.	-
Hexabromodiphenyl ether		mg/kg	5	n.d.	-
Heptabromodiphenyl ether		mg/kg	5	n.d.	-
Octabromodiphenyl ether		mg/kg	5	n.d.	-
Nonabromodiphenyl ether		mg/kg	5	n.d.	-
Decabromodiphenyl ether		mg/kg	5	n.d.	-
Sum of PBDEs		mg/kg	-	n.d.	1000

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Test Item(s)	Method	Unit	MDL	Result No.1	Limit
Butyl benzyl phthalate (BBP)	With reference to IEC 62321-8: 2017, analysis was performed by GC/MS.	mg/kg	50	n.d.	1000
Dibutyl phthalate (DBP)		mg/kg	50	n.d.	1000
Diisobutyl phthalate (DIBP)		mg/kg	50	n.d.	1000
Di-(2-ethylhexyl) phthalate (DEHP)		mg/kg	50	n.d.	1000
Diisononyl phthalate (DINP) (CAS No.: 28553-12-0, 68515-48-0)		mg/kg	50	n.d.	-
Diisodecyl phthalate (DIDP) (CAS No.: 26761-40-0, 68515-49-1)		mg/kg	50	n.d.	-
Di-n-octyl phthalate (DNOP) (CAS No.: 117-84-0)		mg/kg	50	n.d.	-
Di-n-pentyl phthalate (DNPP) (CAS No.: 131-18-0)		mg/kg	50	n.d.	-
Antimony (Sb) (CAS No.: 7440-36-0)	With reference to US EPA 3052: 1996, analysis was performed by ICP-OES.	mg/kg	2	n.d.	-
Beryllium (Be) (CAS No.: 7440-41-7)	With reference to US EPA 3052: 1996, analysis was performed by ICP-OES.	mg/kg	2	n.d.	-
Arsenic (As) (CAS No.: 7440-38-2)	With reference to US EPA 3052: 1996, analysis was performed by ICP-OES.	mg/kg	2	n.d.	-
Fluorine (F) (CAS No.: 14762-94-8)	With reference to BS EN 14582: 2016, analysis was performed by IC.	mg/kg	50	n.d.	-
Chlorine (Cl) (CAS No.: 22537-15-1)	With reference to BS EN 14582: 2016, analysis was performed by IC.	mg/kg	50	n.d.	-
Bromine (Br) (CAS No.: 10097-32-2)	With reference to BS EN 14582: 2016, analysis was performed by IC.	mg/kg	50	n.d.	-
Iodine (I) (CAS No.: 14362-44-8)	With reference to BS EN 14582: 2016, analysis was performed by IC.	mg/kg	50	n.d.	-

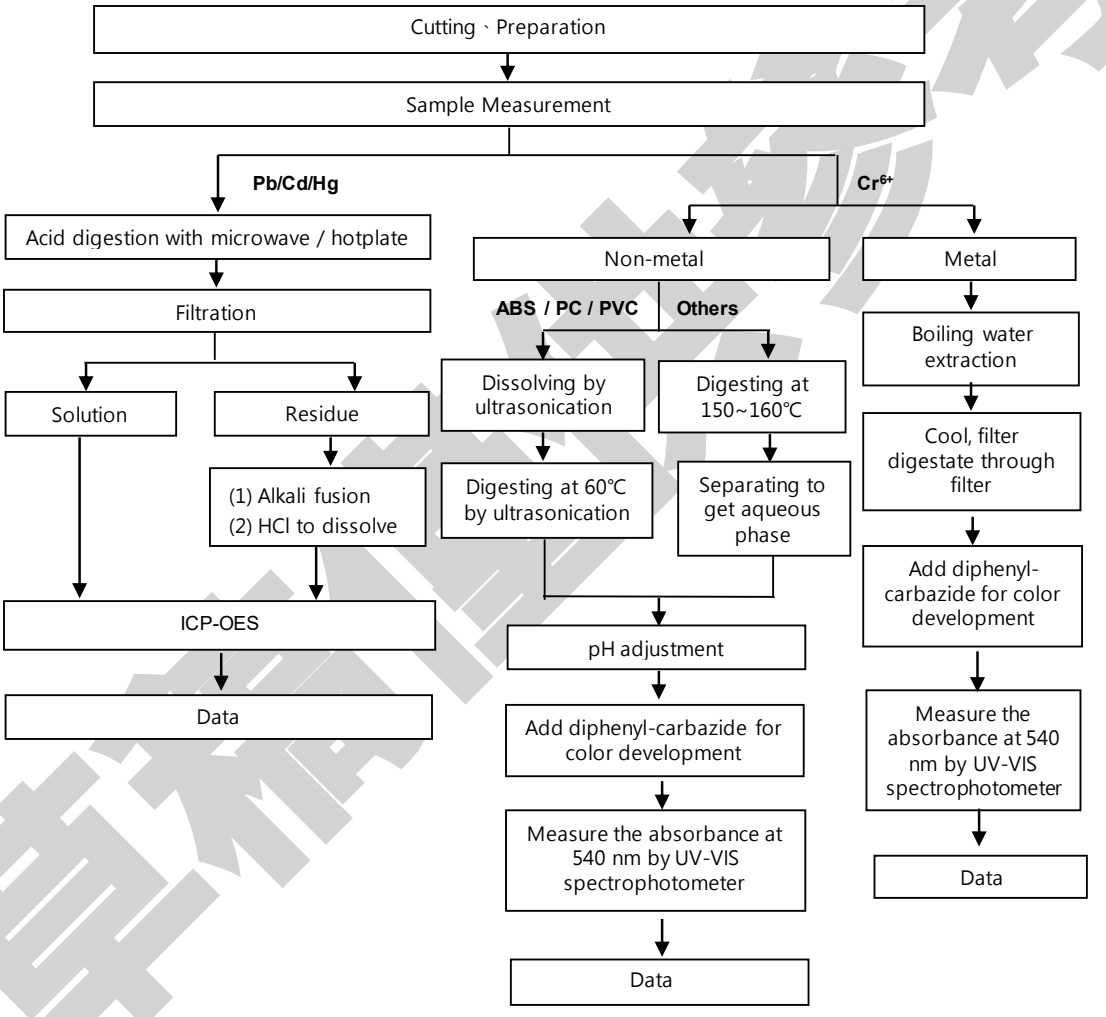
Note：

1. mg/kg = ppm ; 0.1wt% = 0.1% = 1000ppm
2. MDL = Method Detection Limit
3. n.d. = Not Detected (Less than MDL)
4. "-" = Not Regulated
5. Unless otherwise stated , the decision rule for conformity reporting is based on Binary Statement for Simple Acceptance Rule (w=0) stated in ILAC-G8:09/2019. According to this rule, the judgement of conformity is based on the comparing test results with limits.

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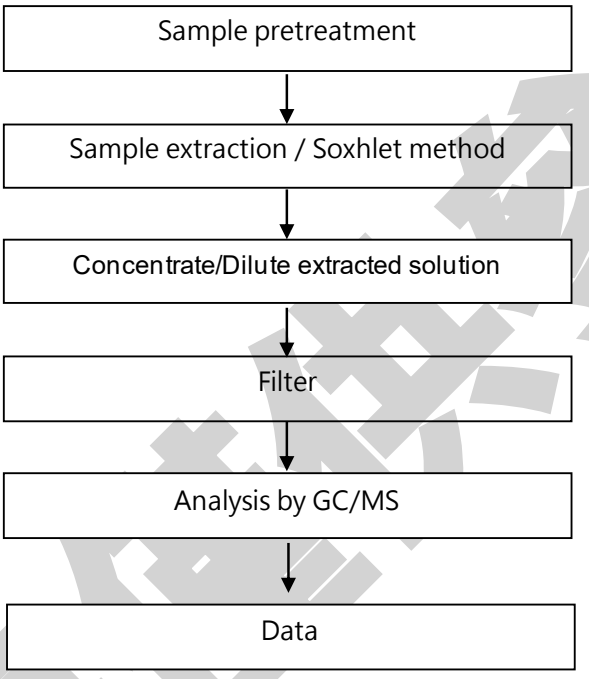
Analytical flow chart of Heavy Metal

These samples were dissolved totally by pre-conditioning method according to below flow chart.
(Cr^{6+} test method excluded)



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PBB/PBDE analytical FLOW CHART

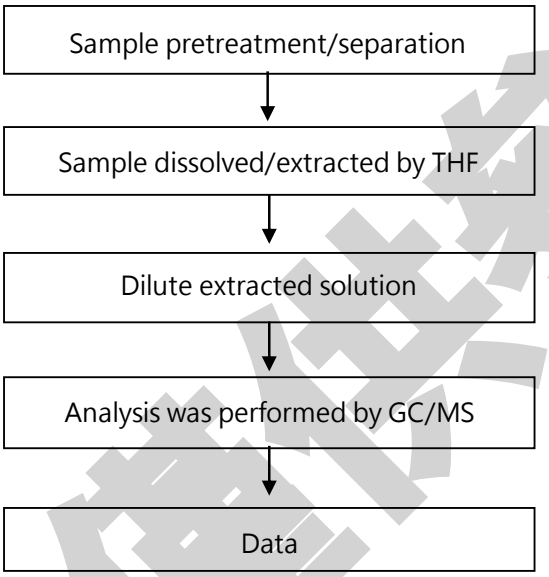


草稿仅供参考

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Analytical flow chart of phthalate content

【Test method: IEC 62321-8】



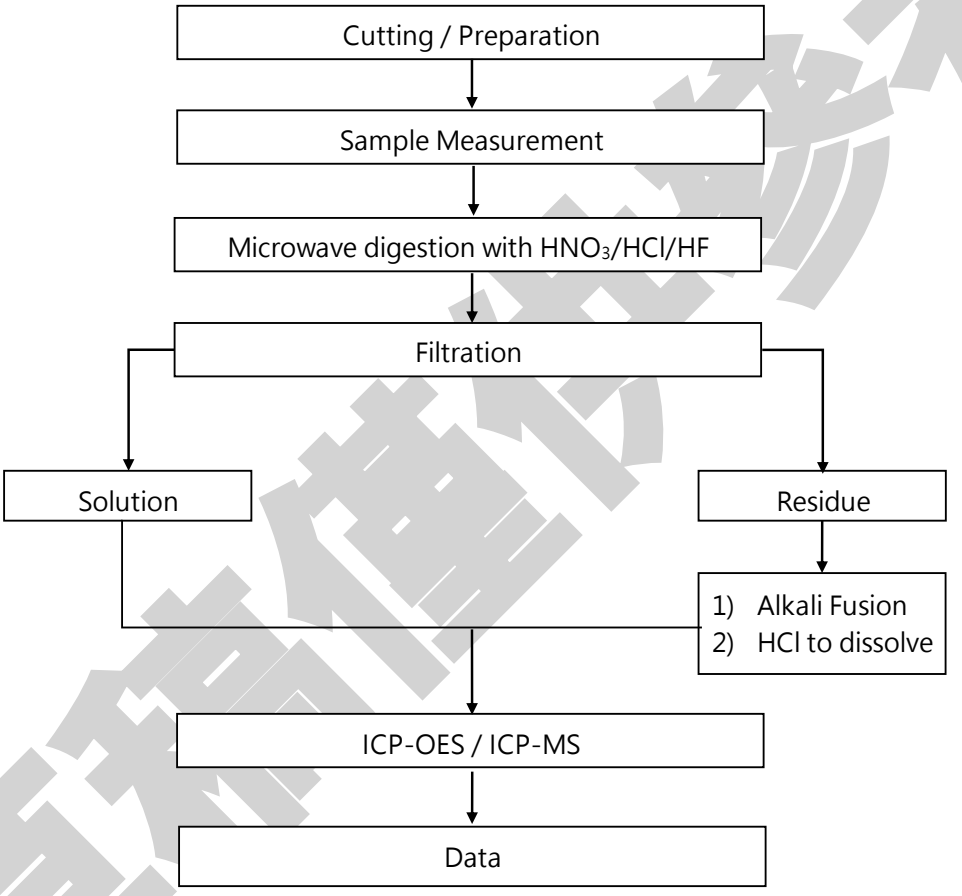
草稿信息

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Analytical flow chart of Elements (Heavy metal included)

These samples were dissolved totally by pre-conditioning method according to below flow chart.

【Reference method：US EPA 3051、US EPA 3052】

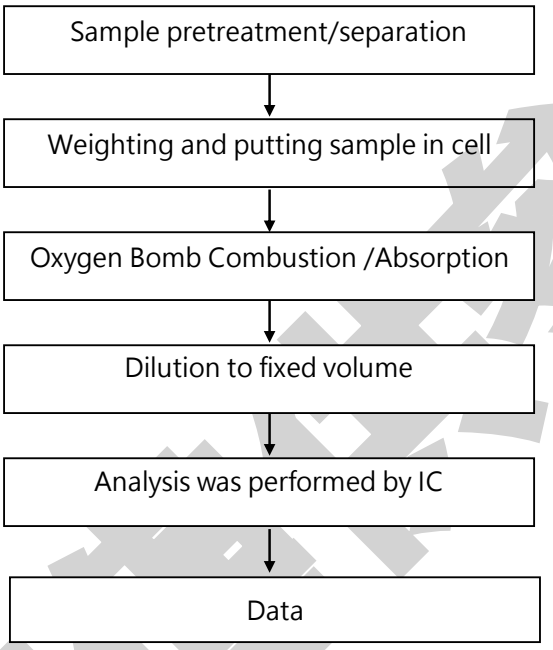


* US EPA 3051 method does not add HF.

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Analytical flow chart of Halogen

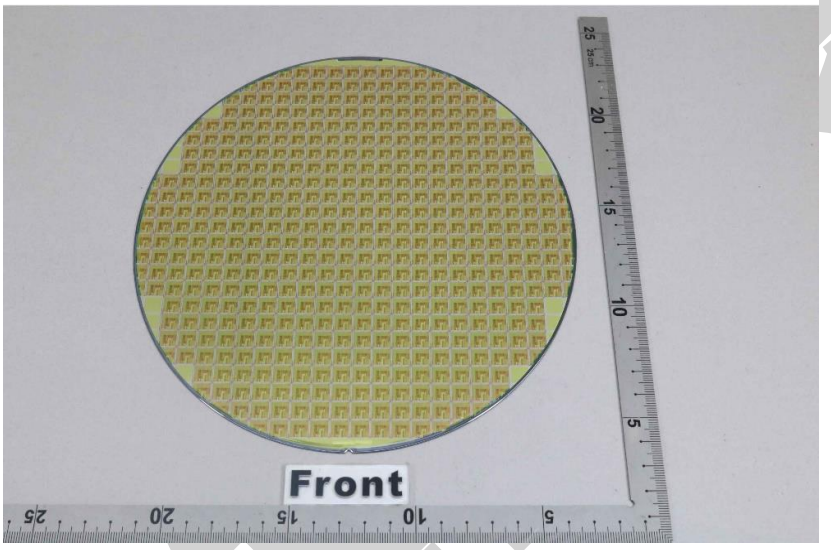


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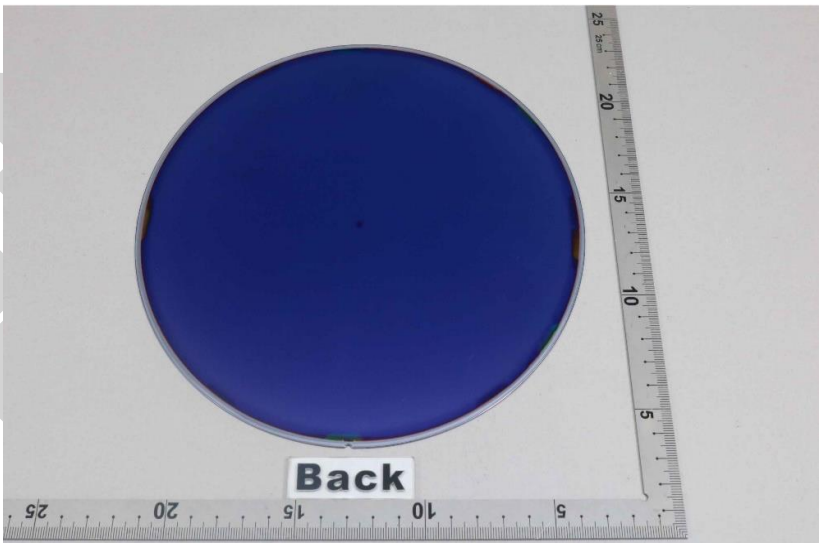
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*** The tested sample / part is marked by an arrow if it's shown on the photo. ***

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** End of Report **